

## Clock Pulse Generator/Driver

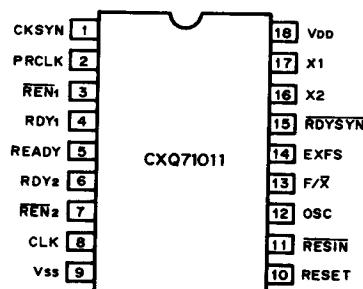
### Description

The CXQ71011 is a clock pulse generator/driver for microprocessors and their peripherals with high speed CMOS technology.

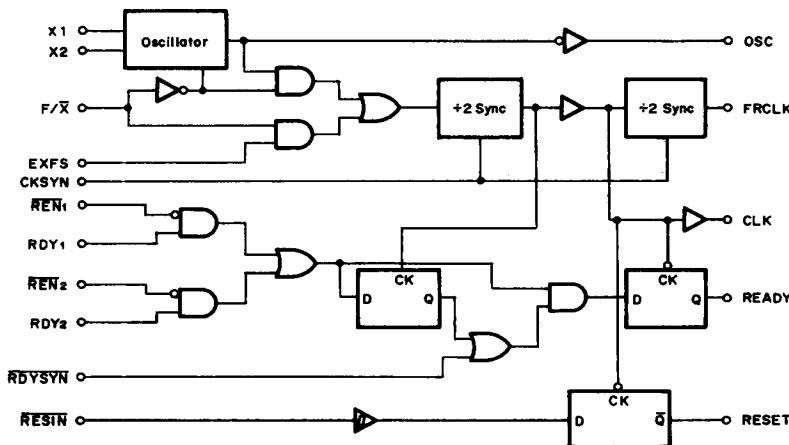
### Features

- Clock pulse generator/driver for CXQ70108/70116 CPUs and their peripherals
- Frequency source can be a crystal or an external clock
- Internal frequency source power-down mode available when external clock is used ( $F/\bar{X} = 'H'$ )
- Reset signal with Schmitt-trigger circuit for CPU or peripherals
- Bus ready signal with two-bus system synchronization
- Clock synchronization with other CXQ71011s
- CMOS technology
- +5V single power supply
- 18-pin plastic DIP (300 mil)
- NEC  $\mu$ PD71011 compatible

### Pin Configuration (Top View)



### Block Diagram



**Pin Identification**

No.	Symbol	Direction	Function
1	CKSYN	In	Clock synchronization input
2	PRCLK	Out	Peripheral clock output
3	$\overline{REN}_1$	In	Bus ready enable input 1
4	RDY <sub>1</sub>	In	Bus ready input 1
5	READY	Out	Ready output
6	RDY <sub>2</sub>	In	Bus ready input 2
7	$\overline{REN}_2$	In	Bus ready enable input 2
8	CLK	Out	Processor clock output
9	Vss		Ground
10	RESET	Out	Reset output
11	$\overline{RESIN}$	In	Reset input
12	OSC	Out	Oscillator output
13	F/ $\overline{X}$	In	External frequency source/crystal select
14	EXFS	In	External frequency source input
15	$\overline{RDYSYN}$	In	Ready synchronization select
16	X2	In	Crystal input
17	X1	In	Crystal input
18	V <sub>DD</sub>		Power supply

**Pin Functions****X1, X2 [Crystal Inputs]**

A crystal is connected to these inputs to generate clocks for a CPU and its peripherals. The crystal frequency should be two times the frequency of CLK.

**EXFS [External Frequency Source Input]**

EXFS is external frequency input in the external frequency source mode ( $F/\overline{X} = 'H'$ ). A square TTL-level clock signal of two times the frequency of CLK output should be used for the source.

**F/ $\overline{X}$  [Frequency/Crystal Select]**

$F/\overline{X}$  selects either the external frequency source or the crystal as the source of the CLK output. When  $F/\overline{X}$  is low, CLK is generated from the crystal connected to X1 and X2. When  $F/\overline{X}$  is high, CLK is generated from an external TTL-level frequency input on the EXFS pin and at the same time, the internal oscillation circuit will go into the power-down mode.

**CLK [Processor Clock]**

CLK supplies a 50% duty cycle clock to drive the CPU and its peripherals on the local bus. CLK has a half frequency of crystal or EXFS input. The CLK output is +0.4V higher than the other outputs.

**PRCLK [Peripheral Clock]**

PRCLK supplies a 50% duty cycle clock at one-half the frequency of CLK to drive peripheral devices.

**OSC [Oscillator]**

OSC outputs a TTL-level signal at the same frequency as the crystal input.

**CKSYN [Clock Synchronization]**

CKSYN synchronizes one CXQ71011 to other CXQ71011s. A high level at CKSYN resets the internal counter, and a low level enables it to count. CKSYN needs to be externally synchronized to EXFS. When using the crystal oscillator, CKSYN needs to be stopped to ground.

**RESIN [Reset Input]**

This Schmitt trigger input generates the RESET output. An RC connection can be used to provide power-on-reset.

**RESET [Reset]**

This output is a reset signal for the CPU.

**RDY<sub>1</sub>, RDY<sub>2</sub> [Bus Ready]**

A peripheral device sends RDY<sub>1</sub> or RDY<sub>2</sub> to signal that the data on the system bus has been received or is ready to be sent. REN<sub>1</sub> and REN<sub>2</sub> control the RDY<sub>1</sub> and RDY<sub>2</sub> signals.

**REN<sub>1</sub>, REN<sub>2</sub> [Bus Ready Enable]**

REN<sub>1</sub> and REN<sub>2</sub> qualify their respective RDY inputs.

**RDYSYN [Ready Synchronization Select]**

RDYSYN selects the mode of READY signal synchronization. A low-level signal makes the synchronization a two-step process. This is used when RDY<sub>1</sub> and RDY<sub>2</sub> inputs are not synchronized to CLK. A high-level signal makes synchronization a one-step process. This is used when RDY<sub>1</sub> and RDY<sub>2</sub> are synchronized to CLK. See Block Diagram.

**READY [Ready]**

The READY signal to the processor is synchronized by the RDY inputs to the processor CLK. READY is cleared after the guaranteed hold time of the processor.

**Absolute Maximum Ratings**

(Ta=25°C, Vss=0V)

Parameter	Symbol	Rating Value	Unit
Power supply voltage	V <sub>DD</sub>	-0.5 to +7.0	V
Input voltage	V <sub>I</sub>	-1.0 to V <sub>DD</sub> +1.0	V
Output voltage	V <sub>O</sub>	-0.5 to V <sub>DD</sub> +0.5	V
Power dissipation	P <sub>DMAX</sub>	500	mW
Operating temperature	T <sub>opr</sub>	-40 to +85	°C
Storage temperature	T <sub>stg</sub>	-65 to +150	°C

**Comment:** Exposing the device to stresses above those listed in the absolute maximum ratings could cause permanent damage. Exposure to absolute maximum ratings for extended periods may affect device reliability.

**DC Characteristics**

(Ta=−40 to +85°C, VDD=5V±10%)

Parameter	Symbol	Min.	Max.	Unit	Test Conditions
Input voltage high	VIH	2.2		V	
Input voltage high	VIH	2.6		V	RESIN only
Input voltage low	VIL		0.8	V	
Output voltage high	VOH	VDD−0.8		V	I <sub>OH</sub> =−4 mA
Output voltage high	VOH	VDD−0.4		V	CLK, I <sub>OH</sub> =−4 mA
Output voltage low	VOL		0.45	V	I <sub>OL</sub> =4 mA
Input current leakage	I <sub>IL</sub>	−1.0	1.0	μA	
RDYSYN input current	I <sub>I</sub>	−400	1.0	μA	
RESIN input hysteresis	V <sub>H</sub>	0.25		V	
Power supply current (dynamic)	I <sub>DDdyn</sub>		30	mA	f <sub>IN</sub> =20 MHz
Power supply current (static)	I <sub>DD</sub>		200	μA	

**Capacitance**

(Ta=25°C, VDD=+5V)

Parameter	Symbol	Min.	Max.	Unit	Test Conditions
Input capacitance	C <sub>IN</sub>		12	pF	f <sub>c</sub> =1 MHz

**AC Characteristics**

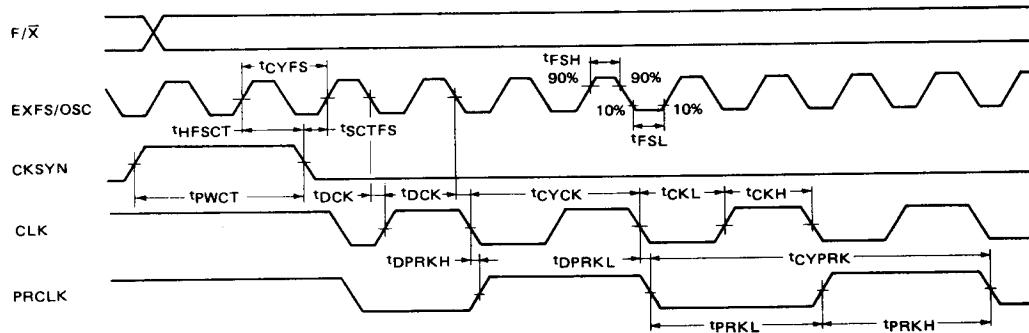
$$\begin{cases} \text{fosc}=10 \text{ MHz: } Ta=-40 \text{ to } +85^\circ\text{C, } VDD=5V\pm10\% \\ \text{fosc}=16 \text{ MHz: } Ta=-10 \text{ to } +70^\circ\text{C, } VDD=5V\pm5\% \end{cases}$$

Parameter	Symbol	Min.	Max.	Unit	Test Conditions
EXFS cycle time	t <sub>CYFS</sub>	50		ns	
EXFS high	t <sub>FSH</sub>	20		ns	90%—90% V <sub>IN</sub>
EXFS low	t <sub>FSL</sub>	20		ns	10%—10% V <sub>IN</sub>
OSC frequency	f <sub>osc</sub>	8	20	MHz	
CKSYN width	t <sub>PWCT</sub>	2t <sub>CYFS</sub>		ns	
CKSYN hold for EXFS (active)	t <sub>HFSCST</sub>	20		ns	
CKSYN setup (inactive)	t <sub>SCTFS</sub>	20		ns	
CLK cycle time	t <sub>CYCK</sub>	125		ns	
CLK high	t <sub>CKH</sub>	50		ns	Test point 3.0V, fosc=16 MHz
		80		ns	Test point 3.0V, fosc=10 MHz

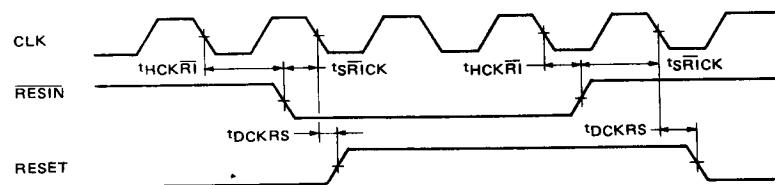
Parameter	Symbol	Min.	Max.	Unit	Test Conditions
CLK low	tCKL	60		ns	Test point 1.5V, fosc=16 MHz
		90		ns	Test point 1.5V, fosc=10 MHz
CLK rise time	tRCK		8	ns	Test point 1.5V to 3.0V, fosc=16 MHz
			10	ns	Test point 1.5V to 3.0V, fosc=10 MHz
CLK fall time	tFCK		7	ns	Test point 3.0V to 1.5V, fosc=16 MHz
			10	ns	Test point 3.0V to 1.5V, fosc=10 MHz
OSC to CLK ↑ delay	tDCK	2	30	ns	
OSC to CLK ↓ delay	tDCK	-6	28	ns	
PRCLK cycle time	tCYPRK	250		ns	
PRCLK high	tPRKH	tCYCK-20		ns	
PRCLK low	tPRKL	tCYCK-20		ns	
CLK ↓ to PRCLK ↑ delay	tDPRKH		22	ns	
CLK ↓ to PRCLK ↓ delay	tDPRKL		22	ns	
RESIN to CLK ↓ setup	tsRICK	65		ns	
CLK ↓ to RESIN hold	tHCKR <small>I</small>	20		ns	
CLK ↓ to RESET delay	tDCKRS		40	ns	
REN <sub>1, 2</sub> to RDY <sub>1, 2</sub> setup	tsRERY	15		ns	
CLK ↓ to REN <sub>1, 2</sub> hold	tHCKR <small>E</small>	0		ns	
RDY <sub>1, 2</sub> to CLK ↓ setup	tsRYCK	35		ns	RDYSYN high
RDY <sub>1, 2</sub> to CLK ↑ setup	tsRYCK	35		ns	RDYSYN low
CLK ↓ to RDY <sub>1, 2</sub> hold	tHCKRY	0		ns	
RDYSYN ↑ to CLK ↓ setup	tsRYSCK	50		ns	
CLK ↓ to RDYSYN ↓ hold	tHCKRYS	0		ns	
CLK ↓ to READY ↑ output delay	tDCKRDY		8	ns	
CLK ↓ to READY ↓ output delay	tDCKRDY		8	ns	
Input rise time	tRI		20	ns	0.8V to 2.0V
Input fall time	tFI		12	ns	2.0V to 0.8V
Output rise time	tRO		20	ns	0.8V to 2.0V
Output fall time	tFO		12	ns	2.0V to 0.8V

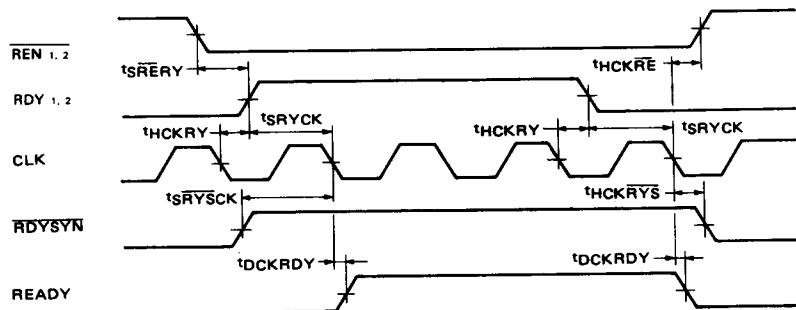
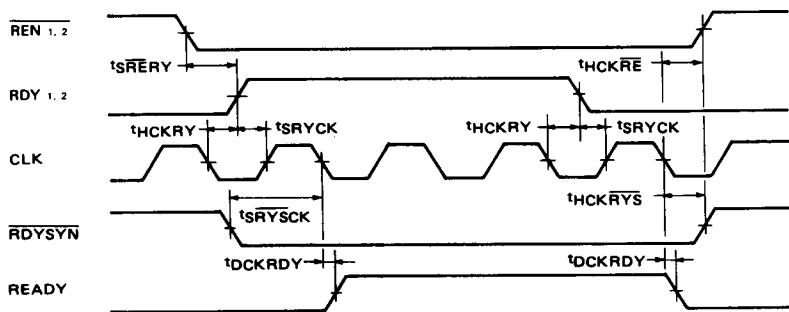
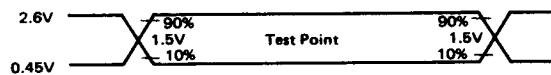
## Timing Waveforms

### Clock Output



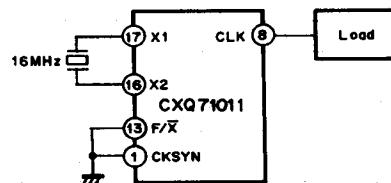
### RESET Output



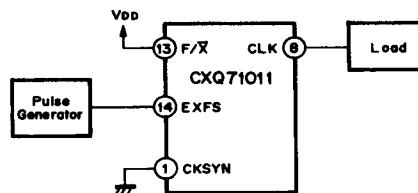
**READY Output (RDYSYN High)****READY Output (RDYSYN Low)****Test Circuit for CLK High or Low Time**

## Test Circuits

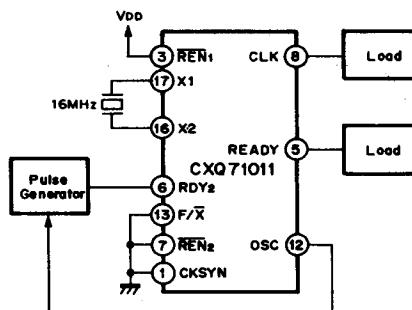
### Test Circuit for CLK High or Low Time (in Crystal Oscillation Mode)

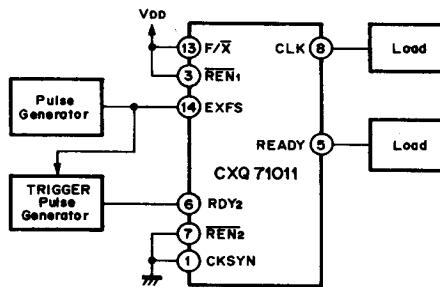
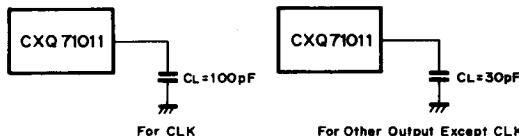


### Test Circuit for CLK High or Low Time (in EXFS Oscillation Mode)



### Test Circuit for CLK to READY (in Crystal Oscillation Mode)



**Test Circuit for CLK to READY (in EXFS Oscillation Mode)****Loading Circuits****Package Outline**

Unit: mm

